Pulsed Laser Deposition of YBCO for High I_c Coated Conductor Development

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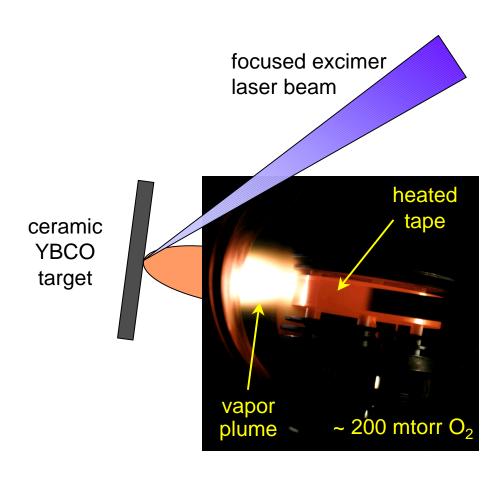




PLD basics

Unique aspects of PLD:

- Energy deposited in the target surface is ~ 1 MJ/cm³ in a 25 ns pulse.
- Deposition consists of short pulses of extremely high rate, separated by relatively long periods with no film growth.
- Optimum YBCO growth requires a balance between laser energy, target-substrate distance, and background pressure.







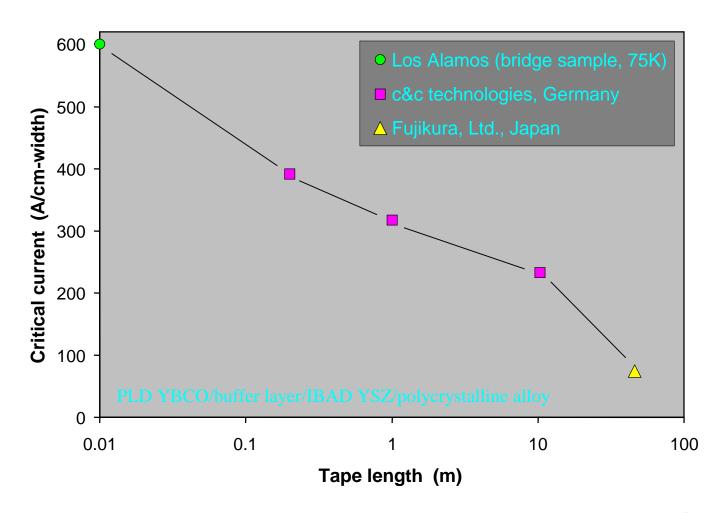
Contributions of PLD to coated conductor development -- highlights

- 1991-2 First coated conductors (textured YBCO on metal) demonstrated.
- 1993 First thick YBCO with high J_c (~ 1 MA/cm² at > 6 μ m thickness single-crystal substrate).
- 1995 First coated conductor with $I_c = 200 \text{ A}$ (1 cm wide).
- 1999 First continuously-processed meter with $I_c > 100 \text{ A}$ (1 cm wide)
- 2000 First coated conductor samples with $I_c > 500$ A/cm-width (200 $\mu m \times 5$ mm bridges).
- today Three companies worldwide are actively investigating commercial production of coated conductors with PLD.





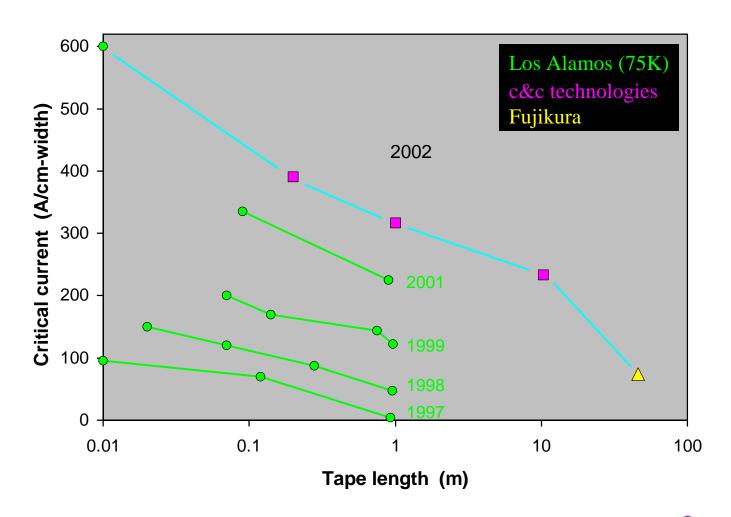
PLD-YBCO coated conductors have the highest critical current values at all length scales







PLD-based conductors have steadily improved







Although the deposition area is small, PLD is capable of processing high-I_c tape at high line speed

- With a 200 W laser, we produced a meter of 1 µm thick x 1 cm wide YBCO in 4 minutes (15 m/h).
- We were able to maintain high J_c at these high deposition rates -- I_c s of 100 200 A are readily achievable at this rate.
- Since this demonstration, a 300 W laser capable of 24/7 operation has come on the market.
- The demonstrated rate extrapolates to ~ 200 km/y for a single 300 W laser running 24/7.
- In the demonstration, only about half of the laser power was getting into the chamber, and less than half of the vapor was collected on tape efficiency can be improved in both areas.





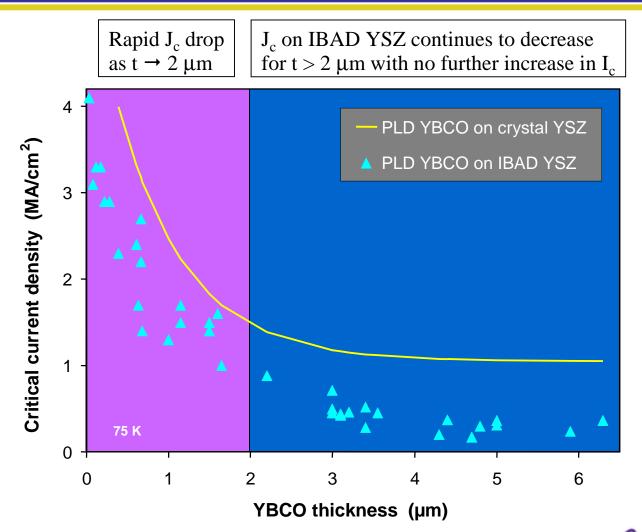
Conclusions (PLD)

- PLD is a fast, simple, and reliable way to deposit YBCO and/or essentially any buffer layer needed for coated conductors.
- PLD has led the way in coated conductor development and continues to produce tapes with the best performance.
- Three companies are actively investigating PLD as a route to commercial production of coated conductors.





The "thick film problem" we previously reported for IBAD YSZ-based coated conductors has two parts







Process modifications solve the t > 2 μ m problem; I_c values of 300 – 400 A/cm-width on IBAD YSZ are routinely achieved

Successful process modifications include:

- Multilayers (first reported at 2000 Peer Review)
- Certain mixtures of RE123 materials
- High *instantaneous* rate PLD (~ 4 A/shot)





What is the source of the problem at $t > 2 \mu m$?

<u>Hypothesis</u> – J_c continues to drop at $t > 2 \mu m$ because of porosity (i.e. poor connectivity) that evolves in thicker YBCO.

Evidence

- SEM cross-sections show onset of porosity at $\sim 1.5 \, \mu m$
- Thinning experiments show negligible J_c above ~ 1.5 μm
- \bullet When porosity is reduced by process modification, high J_c is observed throughout thick films.





What is the source of the problem at $t > 2 \mu m$? (cont.)

<u>Hypothesis</u> – Porosity results from cumulative roughening of the growing YBCO surface, which reduces the mobility of arriving vapor species.

Evidence

- SEM plan views show greater roughness for thicker YBCO.
- Process modifications that yield high J_c for thick films also yield smoother surfaces
- One process modification high instantaneous rate produces more energetic vapor at the growing surface, thereby enhancing mobility.

<u>Question</u> – How do multilayers or RE mixtures improve mobility and/or reduce roughness and porosity?





Are there other possible solutions?

<u>Hypothesis</u> – If insufficient mobility is the issue, other processes such as low *average* rate PLD, or ex-situ YBCO growth may exhibit less porosity due to longer time-at-temperature.

Evidence – Oak Ridge?

<u>Hypothesis</u> – IBAD YSZ is rough at the surface – starting with a smoother substrate/buffer combination may reduce porosity or delay its onset.

Evidence

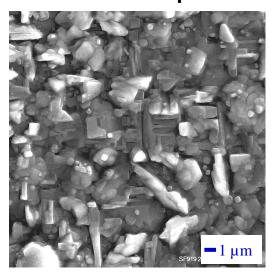
- Original films on single-crystal substrates (with very smooth surfaces) had no porosity and had high J_c throughout YBCO thicknesses of over 6 microns.
- A recent result for thick YBCO on IBAD MgO (which is much smoother than IBAD YSZ) also exhibits high J_c , a smooth surface, and minimal porosity ...





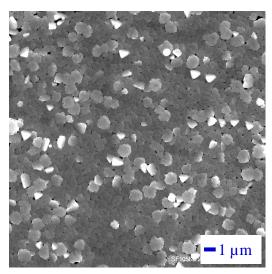
On IBAD MgO/SrRuO₃, which is smoother than IBAD YSZ, high I_c YBCO can be deposited with no process modifications

3.0 µm YBCO on IBAD YSZ -- standard process



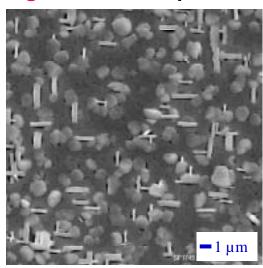
 $J_c = 0.6 \text{ MA/cm}^2$ $I_c = 180 \text{ A/cm-width}$

3.7 µm Y/Sm multilayer on IBAD YSZ



 $J_c = 1.1 \text{ MA/cm}^2$ $I_c = 405 \text{ A/cm-width}$

3.8 µm YBCO on IBAD MgO -- standard process

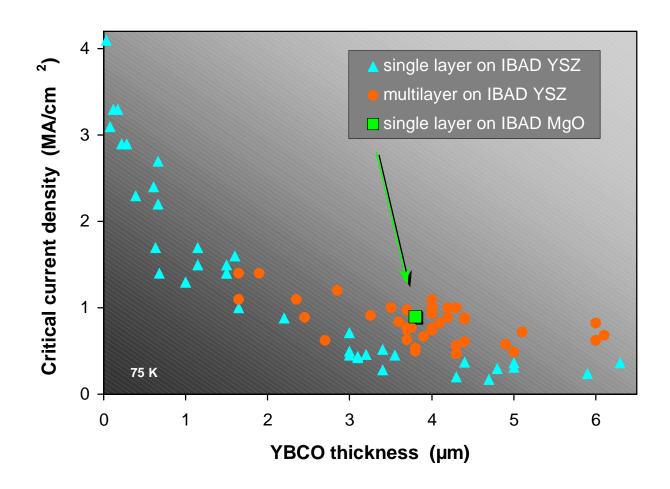


 $J_c = 0.9 \text{ MA/cm}^2$ $I_c = 340 \text{ A/cm-width}$





"Standard" YBCO on IBAD MgO is comparable to our best multilayer coatings on IBAD YSZ







Conclusions (Thick films)

- The problem that keeps I_c from increasing for YBCO thicknesses beyond 2 μm is basically resolved:
 - ⇒ It may be limited to rough starting surfaces (e.g. IBAD YSZ)
 - ⇒ There are several ways to solve the problem
 - ⇒ Very thick YBCO may be commercially impractical
- \bullet The more interesting -- and economically significant -- issue is improving J_c for thinner films ...





... and this is where we will concentrate our future efforts

